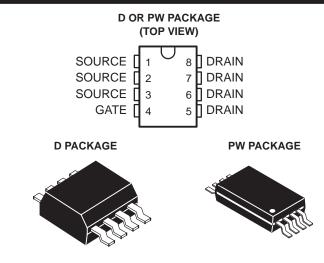
- Low  $r_{DS(on)} \dots 0.18 \Omega$  Typ at  $V_{GS} = -10 \text{ V}$
- 3 V Compatible
- Requires No External V<sub>CC</sub>
- TTL and CMOS Compatible Inputs
- $V_{GS(th)} = -1.5 \text{ V Max}$
- Available in Ultrathin TSSOP Package (PW)
- ESD Protection Up to 2 kV Per MIL-STD-883C, Method 3015

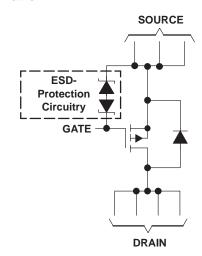
### description

The TPS1100 is P-channel a single enhancement-mode MOSFET. The device has been optimized for 3-V or 5-V power distribution in battery-powered systems by means of Texas Instruments LinBiCMOS™ process. With a maximum V<sub>GS(th)</sub> of -1.5 V and an I<sub>DSS</sub> of only 0.5 μA, the TPS1100 is the ideal high-side switch for low-voltage, portable battery-management systems where maximizing battery life is a primary concern. The low r<sub>DS(on)</sub> and excellent ac characteristics (rise time 10 ns typical) make the TPS1100 the logical choice for low-voltage switching applications such as power switches for pulse-width-modulated (PWM) controllers or motor/bridge drivers.

The ultrathin thin shrink small-outline package or TSSOP (PW) version with its smaller footprint and reduction in height fits in places where other P-channel MOSFETs cannot. The size advantage is especially important where board real estate is at a premium and height restrictions do not allow for a small-outline integrated circuit (SOIC) package.



#### schematic



NOTE A: For all applications, all source pins should be connected and all drain pins should be connected.

#### **AVAILABLE OPTIONS**

	PACKAGED I	PACKAGED DEVICES				
TA	SMALL OUTLINE (D)	PLASTIC DIP (P)	CHIP FORM (Y)			
-40°C to 85°C	TPS1100D	TPS1100PWLE	TPS1100Y			

The D package is available taped and reeled. Add an R suffix to device type (e.g., TPS1100DR). The PW package is available only left-end taped and reeled (indicated by the LE suffix on the device type; e.g., TPS1100PWLE). The chip form is tested at 25°C.



Caution. This device contains circuits to protect its inputs and outputs against damage due to high static voltages or electrostatic fields. These circuits have been qualified to protect this device against electrostatic discharges (ESD) of up to 2 kV according to MIL-STD-883C, Method 3015; however, it is advised that precautions be taken to avoid application of any voltage higher than maximum-rated voltages to these high-impedance circuits.

LinBiCMOS is a trademark of Texas Instruments Incorporated.



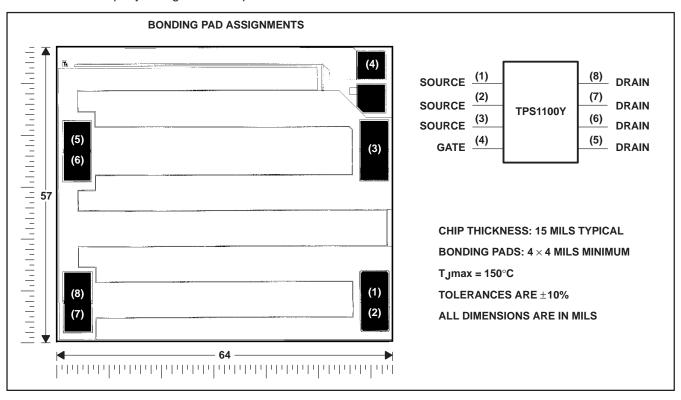
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## description (continued)

Such applications include notebook computers, personal digital assistants (PDAs), cellular telephones, and PCMCIA cards. For existing designs, the D-packaged version has a pinout common with other p-channel MOSFETs in SOIC packages.

## **TPS1100Y** chip information

This chip, when properly assembled, displays characteristics similar to the TPS1100. Thermal compression or ultrasonic bonding may be used on the doped aluminum bonding pads. The chips may be mounted with conductive epoxy or a gold-silicon preform.



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# absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

					UNIT
Drain-to-source voltage, V <sub>DS</sub>				-15	V
Gate-to-source voltage, VGS				2 or –15	V
		D package	T <sub>A</sub> = 25°C	±0.41	
	V22 - 27V	Браскаде	T <sub>A</sub> = 125°C	±0.28	
	$V_{GS} = -2.7 V$	DW pookogo	$T_A = 25^{\circ}C$	±0.4	
Continuous drain current (T <sub>J</sub> = 150°C), I <sub>D</sub> ‡		PW package	T <sub>A</sub> = 125°C	±0.23	
		D package	T <sub>A</sub> = 25°C	±0.6	
	V <sub>GS</sub> = -3 V	Браскаде	T <sub>A</sub> = 125°C	±0.33	
	VGS = -3 V	PW package	T <sub>A</sub> = 25°C	±0.53	Α
		1 W package	T <sub>A</sub> = 125°C	±0.27	
		D package	T <sub>A</sub> = 25°C	±1	
	$V_{GS} = -4.5 \text{ V}$	Браскаде	T <sub>A</sub> = 125°C	±0.47	
	VGS = 1.0 V	PW package	$T_A = 25^{\circ}C$	±0.81	
		1 W package	T <sub>A</sub> = 125°C	±0.37	
		D package	T <sub>A</sub> = 25°C	±1.6	
	V <sub>GS</sub> = -10 V	Браскаде	T <sub>A</sub> = 125°C	±0.72	
	VGS = -10 V	PW package	T <sub>A</sub> = 25°C	±1.27	
		1 W package	T <sub>A</sub> = 125°C	±0.58	
Pulsed drain current, ID <sup>‡</sup>			T <sub>A</sub> = 25°C	±7	Α
Continuous source current (diode conduction), IS			T <sub>A</sub> = 25°C	-1	Α
Storage temperature range, T <sub>Stg</sub>				-55 to 150	°C
Operating junction temperature range, T <sub>J</sub>				-40 to 150	°C
Operating free-air temperature range, T <sub>A</sub>				-40 to 125	°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds				260	°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{$A$}} \leq 25^{\circ}\mbox{$C$}$ POWER RATING	DERATING FACTOR <sup>‡</sup> ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING
D	791 mW	6.33 mW/°C	506 mW	411 mW	158 mW
PW	504 mW	4.03 mW/°C	323 mW	262 mW	101 mW

<sup>‡</sup> Maximum values are calculated using a derating factor based on  $R_{\theta JA} = 158^{\circ}\text{C/W}$  for the D package and  $R_{\theta JA} = 248^{\circ}\text{C/W}$  for the PW package. These devices are mounted on an FR4 board with no special thermal considerations when tested.



<sup>‡</sup> Maximum values are calculated using a derating factor based on R<sub>θJA</sub> = 158°C/W for the D package and R<sub>θJA</sub> = 248°C/W for the PW package. These devices are mounted on a FR4 board with no special thermal considerations.

# TPS1100, TPS1100Y SINGLE P-CHANNEL ENHANCEMENT-MODE MOSFETS

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# electrical characteristics at $T_J = 25^{\circ}C$ (unless otherwise noted)

# static

	PARAMETER	TES	T CONDITION	ie.	1	ΓPS1100		T	PS1100Y	′	UNIT
	PARAMETER	IES	I CONDITIO	MIN	TYP	MAX	MIN	TYP	MAX	UNII	
V <sub>GS(th)</sub>	Gate-to-source threshold voltage	$V_{DS} = V_{GS}$	$I_D = -250 \mu$	A	-1	-1.25	-1.50		-1.25		V
V <sub>SD</sub>	Source-to-drain voltage (diode-forward voltage) <sup>†</sup>	I <sub>S</sub> = -1 A,	V <sub>GS</sub> = 0 V			-0.9			-0.9		V
I <sub>GSS</sub>	Reverse gate current, drain short circuited to source	V <sub>DS</sub> = 0 V,	V <sub>GS</sub> = -12	V			±100				nA
Inno	Zero-gate-voltage drain	V <sub>DS</sub> = -12 V,	\\oo = 0 \\	T <sub>J</sub> = 25°C			-0.5				μА
IDSS	current	VDS = -12 V,	VGS = 0 V	T <sub>J</sub> = 125°C			-10				μΑ
		$V_{GS} = -10 \text{ V}$	$I_D = -1.5 A$			180			180		
	Static drain-to-source	$V_{GS} = -4.5 \text{ V}$	$I_D = -0.5 A$			291	400		291		<b>~</b> 0
rDS(on)	on-state resistance†	$V_{GS} = -3 V$	I <sub>D</sub> = -0.2 A			476	700		476		mΩ
		$V_{GS} = -2.7 \text{ V}$	ID = -0.2 A			606	850		606		
9fs	Forward transconductance†	$V_{DS} = -10 \text{ V},$	I <sub>D</sub> = -2 A			2.5			2.5		S

<sup>†</sup> Pulse test: pulse duration ≤ 300 μs, duty cycle ≤ 2%

# dynamic

	DADAMETED		TEST CONDITIONS					UNIT
	PARAMETER		MIN	TYP	MAX	UNIT		
Qg	Total gate charge					5.45		
Qgs	Gate-to-source charge	$V_{DS} = -10 \text{ V},$	$V_{GS} = -10 \text{ V},$	$I_{D} = -1 A$		0.87		nC
Q <sub>gd</sub>	Gate-to-drain charge					1.4		
td(on)	Turn-on delay time					4.5		ns
td(off)	Turn-off delay time	$V_{DD} = -10 \text{ V},$	$R_{I} = 10 \Omega$	$I_D = -1 A,$		13		ns
t <sub>r</sub>	Rise time	$R_G = 6 \Omega$ ,	See Figures 1 and 2			10		
t <sub>f</sub>	Fall time	]				2		ns
trr(SD)	Source-to-drain reverse recovery time	IF = 5.3 A,	di/dt = 100 A/μs			16		

## PARAMETER MEASUREMENT INFORMATION

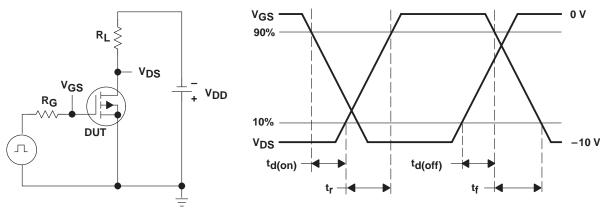


Figure 1. Switching-Time Test Circuit

Figure 2. Switching-Time Waveforms

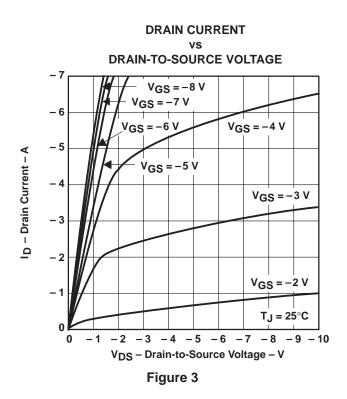
## **TYPICAL CHARACTERISTICS**

# **Table of Graphs**

		FIGURE
Drain current	vs Drain-to-source voltage	3
Drain current	vs Gate-to-source voltage	4
Static drain-to-source on-state resistance	vs Drain current	5
Capacitance	vs Drain-to-source voltage	6
Static drain-to-source on-state resistance (normalized)	vs Junction temperature	7
Source-to-drain diode current	vs Source-to-drain voltage	8
Static drain-to-source on-state resistance	vs Gate-to-source voltage	9
Gate-to-source threshold voltage	vs Junction temperature	10
Gate-to-source voltage	vs Gate charge	11



### TYPICAL CHARACTERISTICS



# **GATE-TO-SOURCE VOLTAGE** -7 $V_{DS} = -10 \text{ V}$ -6 T<sub>J</sub> = 25°C TJ = 150°C - 5 D - Drain Current - A $T_J = -40^{\circ}C$ - 4 - 3 - 2 - 1 0 -6 -7 V<sub>GS</sub> - Gate-to-Source Voltage - V Figure 4

**DRAIN CURRENT** 

# **DRAIN CURRENT** 0.7 T<sub>J</sub> = 25°C 0.6 DS(on) - Static Drain-to-Source $V_{GS} = -2.7 V$ On-State Resistance – $\Omega$ 0.5 $V_{GS} = -3 V$ 0.4 $V_{GS} = -4.5 V$ 0.3 V<sub>GS</sub> = -10 V 0.2 0.1 - 0.1 - 10

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

# **CAPACITANCE** vs **DRAIN-TO-SOURCE VOLTAGE** 350 $V_{GS} = 0$ f = 1 MHz300 T<sub>J</sub> = 25°C C<sub>iss</sub>† 250 C - Capacitance - pF 200 Coss 150 100 c<sub>rss</sub>‡ 50 0 -1 -2 -3 -4 -5 -6 -7 -8 -9 -10 -11 -12 V<sub>DS</sub> - Drain-to-Source Voltage - V $\dagger C_{iss} = C_{gs} + C_{gd}, C_{ds(shorted)}$ $\ddagger C_{rss} = C_{gd}, C_{oss} = C_{ds} + \frac{C_{gs} C_{gd}}{C_{gs} + C_{gd}} \approx C_{ds} + C_{gd}$

Figure 5

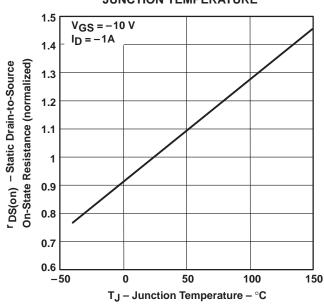
ID - Drain Current - A

Figure 6

#### TYPICAL CHARACTERISTICS

# STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE (NORMALIZED)

# JUNCTION TEMPERATURE



## Figure 7

# SOURCE-TO-DRAIN DIODE CURRENT vs

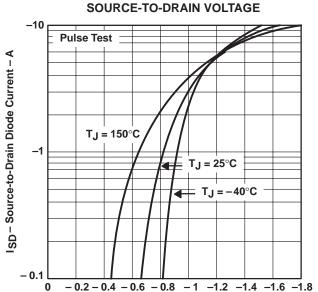


Figure 8

# STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

# GATE-TO-SOURCE VOLTAGE

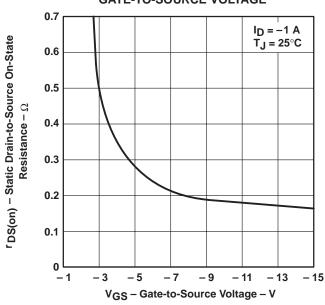


Figure 9

# GATE-TO-SOURCE THRESHOLD VOLTAGE vs

V<sub>SD</sub> - Source-to-Drain Voltage - V

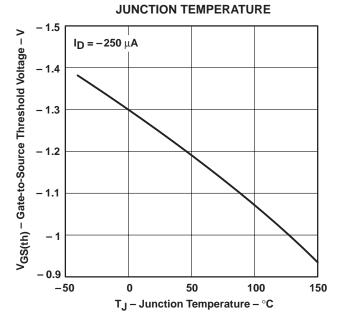


Figure 10

## TYPICAL CHARACTERISTICS

## GATE-TO-SOURCE VOLTAGE vs GATE CHARGE

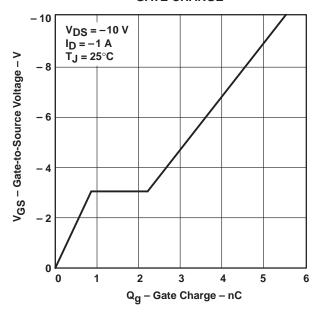


Figure 11

#### THERMAL INFORMATION

#### TRANSIENT JUNCTION-TO-AMBIENT **DRAIN CURRENT** THERMAL IMPEDANCE **DRAIN-TO-SOURCE VOLTAGE PULSE DURATION** -10100 Single Pulse 0.001 s Single Pulse See Note A See Note A $Z_{\theta JA}$ – Transient Junction-to-Ambient 0.01 s Thermal Impedance - °C/W I<sub>D</sub> – Drain Current – A 10 0.1 s 10 s 0.1 DC T」= 150°C TA = 25°C 0.1 -0.0010.001 0.01 -0.1-10 - 100 0.1 V<sub>DS</sub> - Drain-to-Source Voltage - V tw - Pulse Duration - s Figure 12 Figure 13

NOTE A: Values are for the D package and are FR4-board mounted only.

## **APPLICATION INFORMATION**

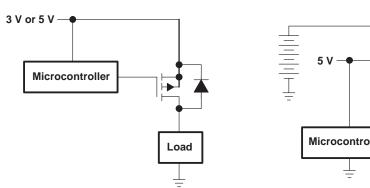


Figure 14. Notebook Load Management

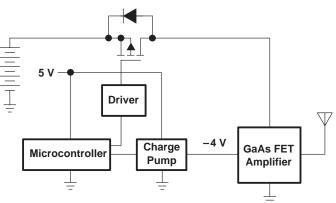


Figure 15. Cellular Phone Output Drive

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
	(1)	(2)			(3)	(4)	(5)		(6)
TPS1100D	Active	Production	SOIC (D)   8	75   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-	1100
TPS1100D.A	Active	Production	SOIC (D)   8	75   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	See TPS1100D	1100
TPS1100DR	Active	Production	SOIC (D)   8	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-	1100
TPS1100DR.A	Active	Production	SOIC (D)   8	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	See TPS1100DR	1100
TPS1100DR.B	Active	Production	SOIC (D)   8	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	See TPS1100DR	1100
TPS1100PW	Active	Production	TSSOP (PW)   8	150   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-	PS1100
TPS1100PW.A	Active	Production	TSSOP (PW)   8	150   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	See TPS1100PW	PS1100
TPS1100PW.B	Active	Production	TSSOP (PW)   8	150   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	See TPS1100PW	PS1100
TPS1100PWR	Active	Production	TSSOP (PW)   8	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-	PS1100
TPS1100PWR.A	Active	Production	TSSOP (PW)   8	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	See TPS1100PWR	PS1100

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



# PACKAGE OPTION ADDENDUM

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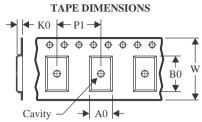
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

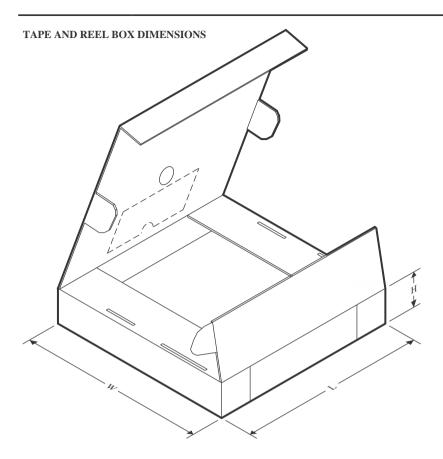


#### \*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS1100DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TPS1100PWR	TSSOP	PW	8	2000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1

# **PACKAGE MATERIALS INFORMATION**

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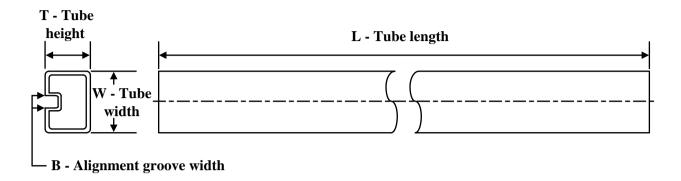
## \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS1100DR	SOIC	D	8	2500	353.0	353.0	32.0
TPS1100PWR	TSSOP	PW	8	2000	353.0	353.0	32.0

# **PACKAGE MATERIALS INFORMATION**

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## **TUBE**



\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TPS1100D	D	SOIC	8	75	507	8	3940	4.32
TPS1100D.A	D	SOIC	8	75	507	8	3940	4.32
TPS1100PW	PW	TSSOP	8	150	530	10.2	3600	3.5
TPS1100PW.A	PW	TSSOP	8	150	530	10.2	3600	3.5
TPS1100PW.B	PW	TSSOP	8	150	530	10.2	3600	3.5

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